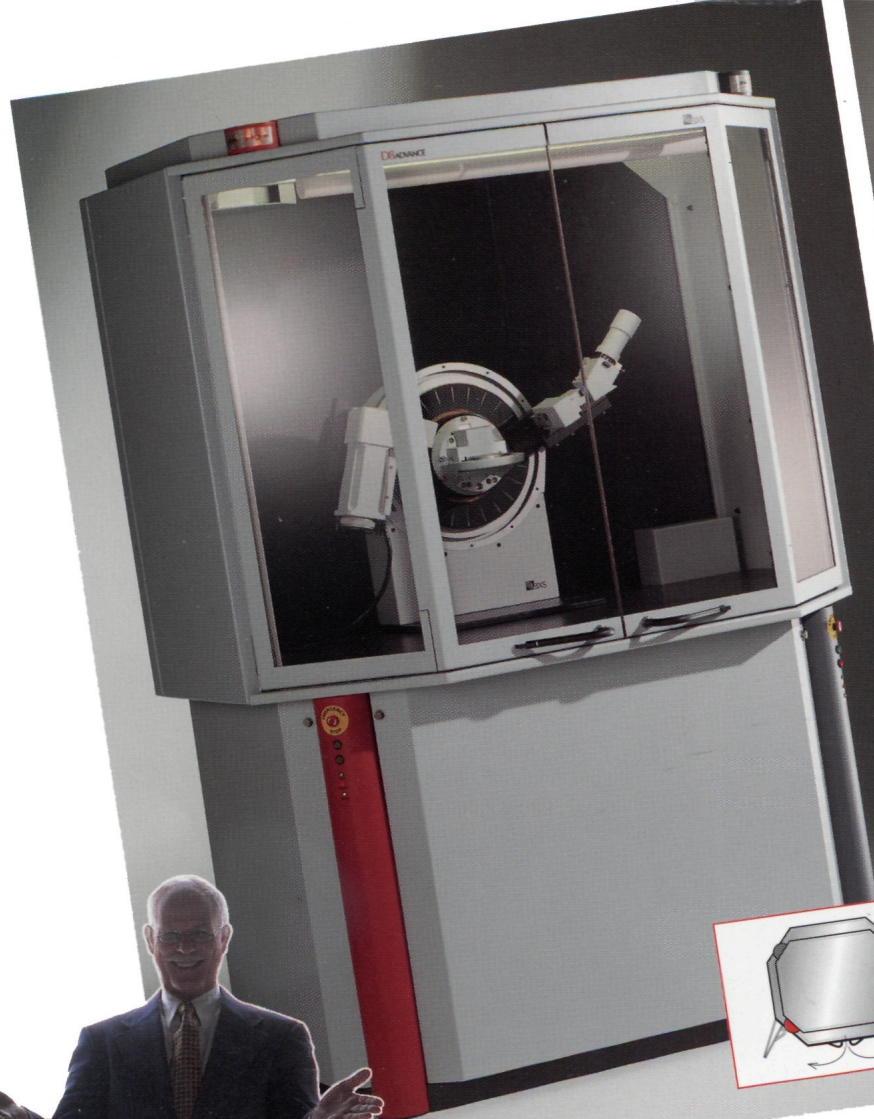
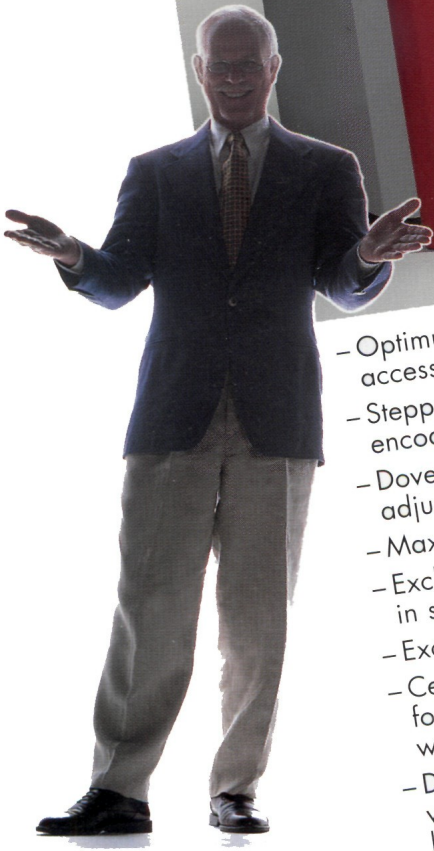
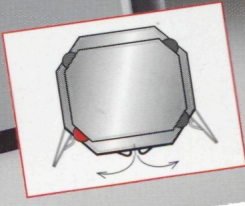
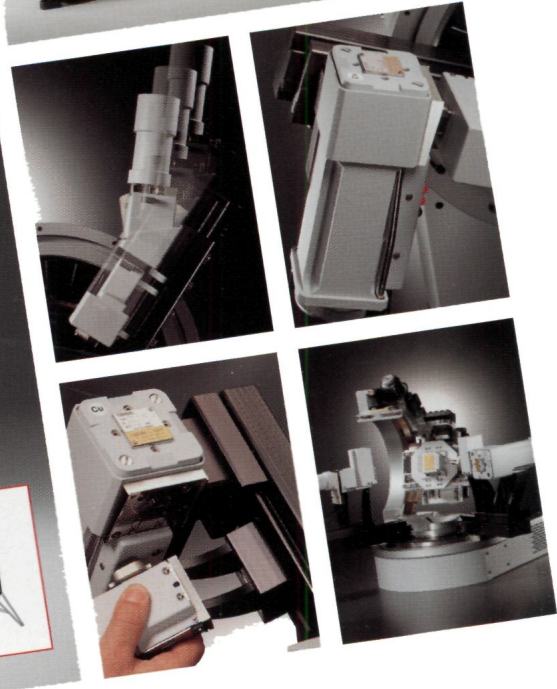


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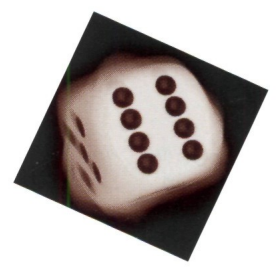
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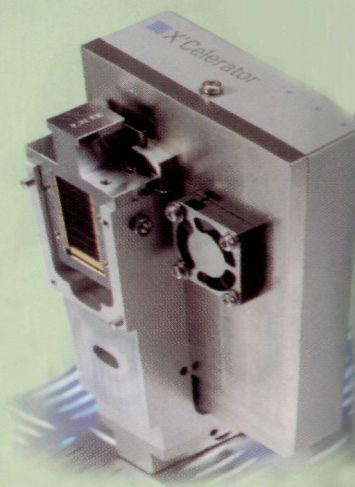
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On the cover: The Ba-O network of $\text{Ba}_5\text{R}_2\text{Zn}_4\text{O}_{21}$. There are two independent Ba: Ba1 is inside a BaO_{10} cage, whereas Ba2 is inside an irregular BaO_{11} cage. Courtesy of W. Wong-Ng, J. A. Kaduk and J. Dillingham.

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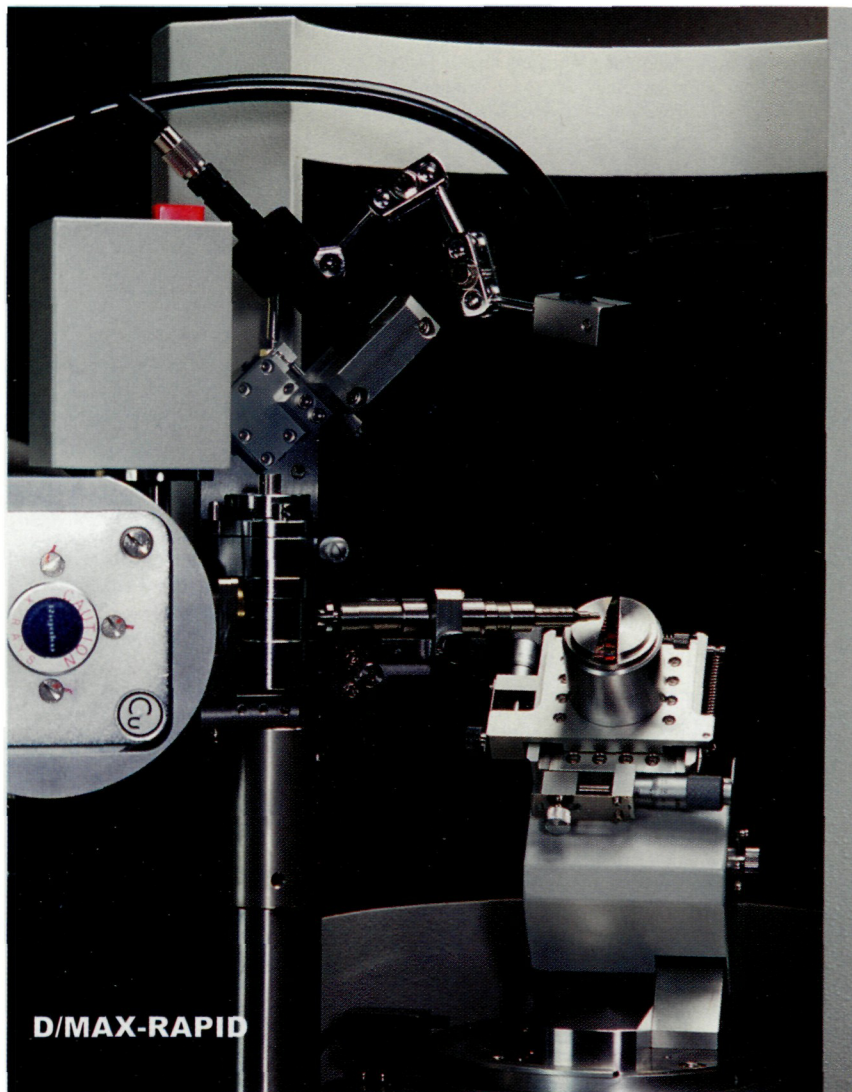
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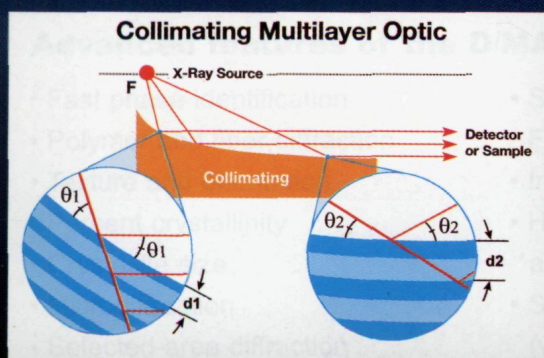
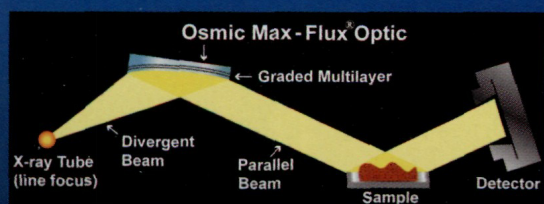
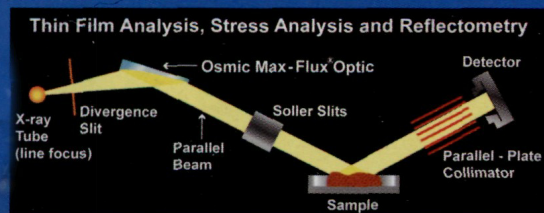
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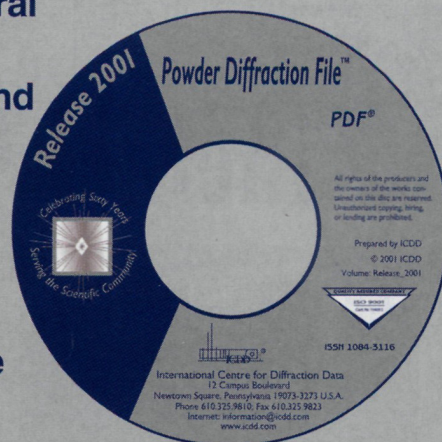
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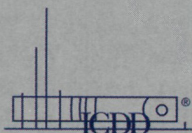
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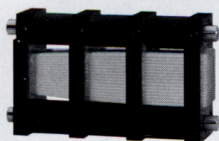
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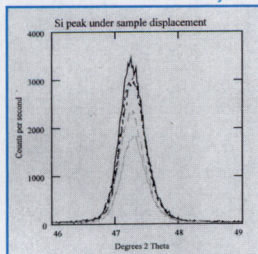
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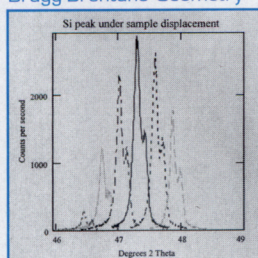
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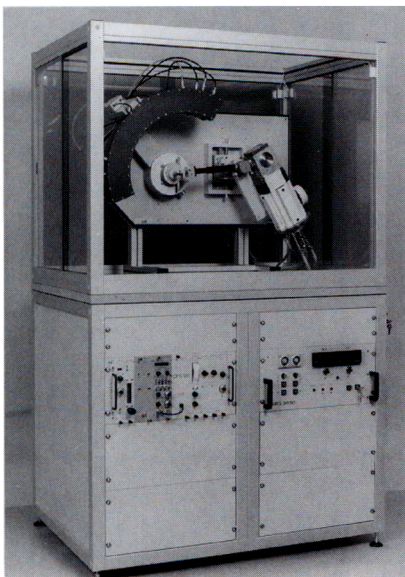
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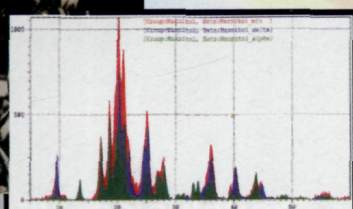
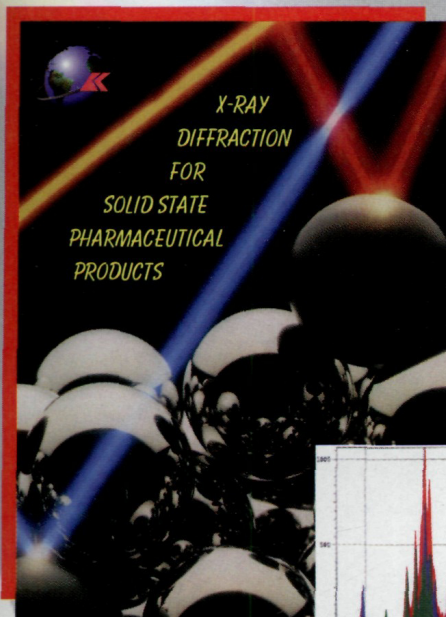
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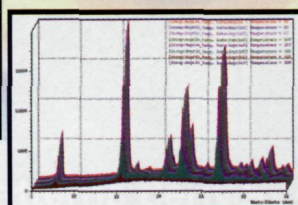
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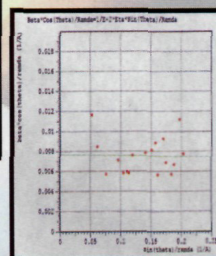
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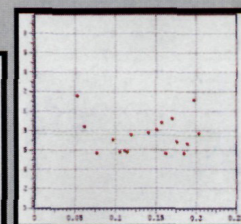
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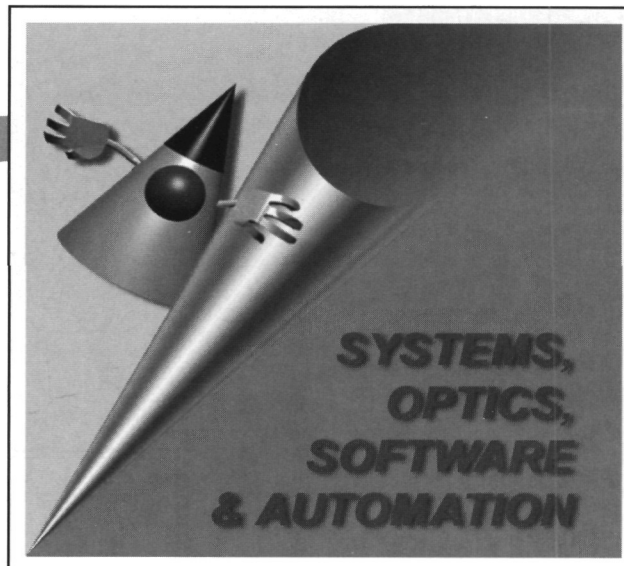
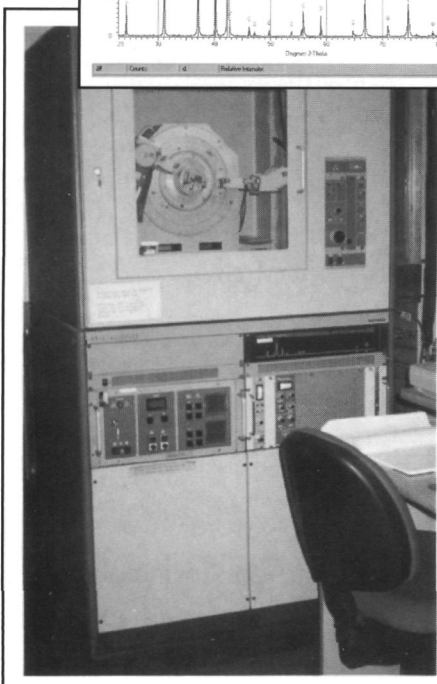
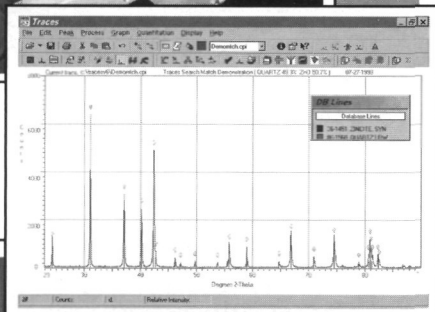
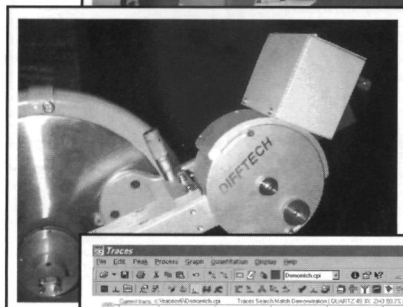
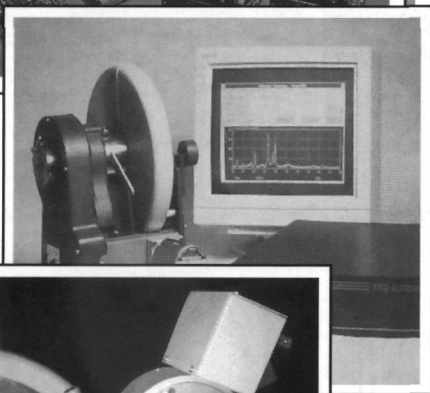
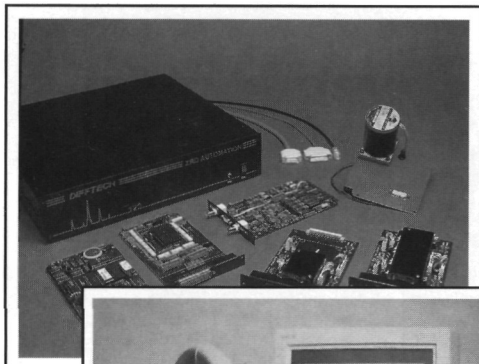


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
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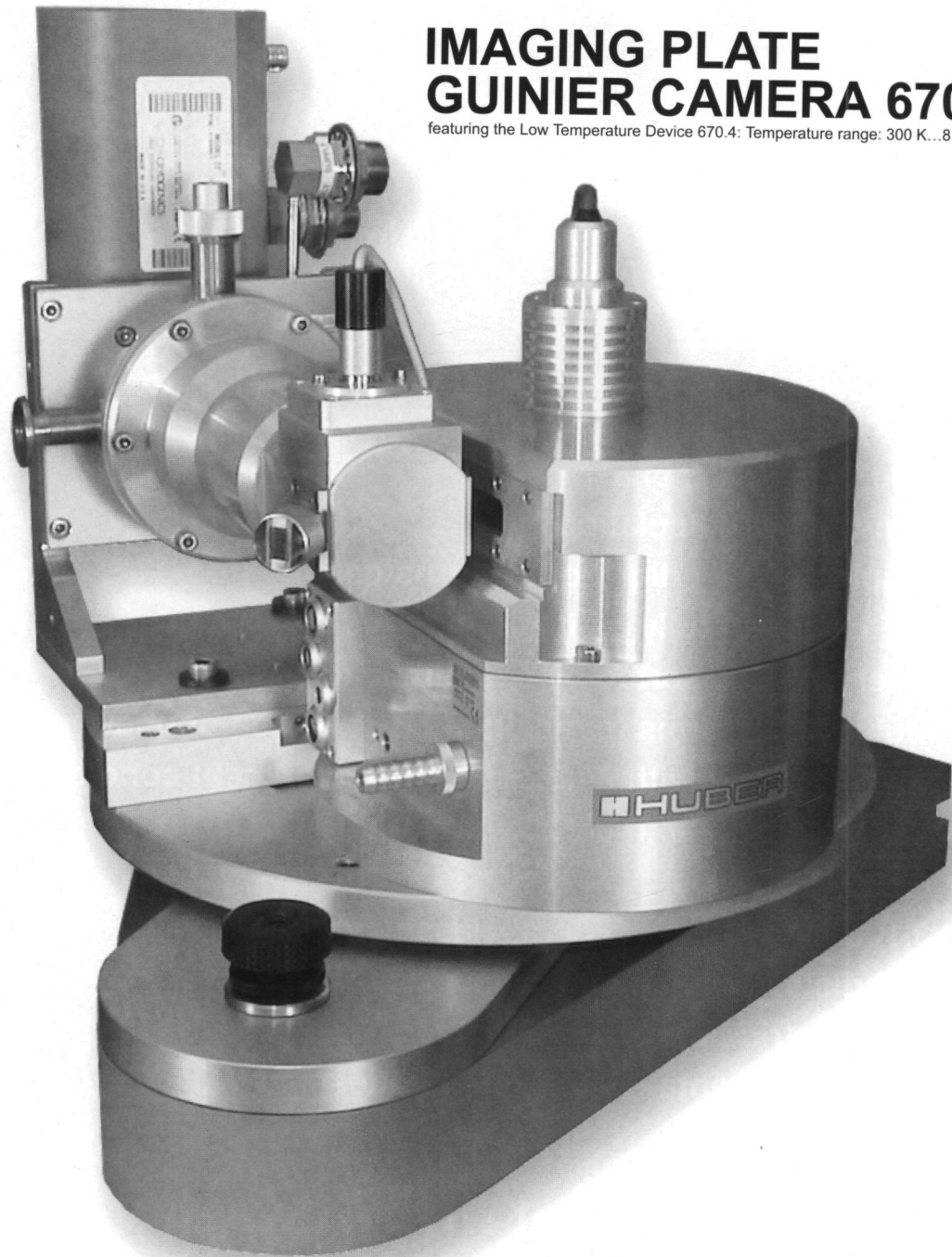
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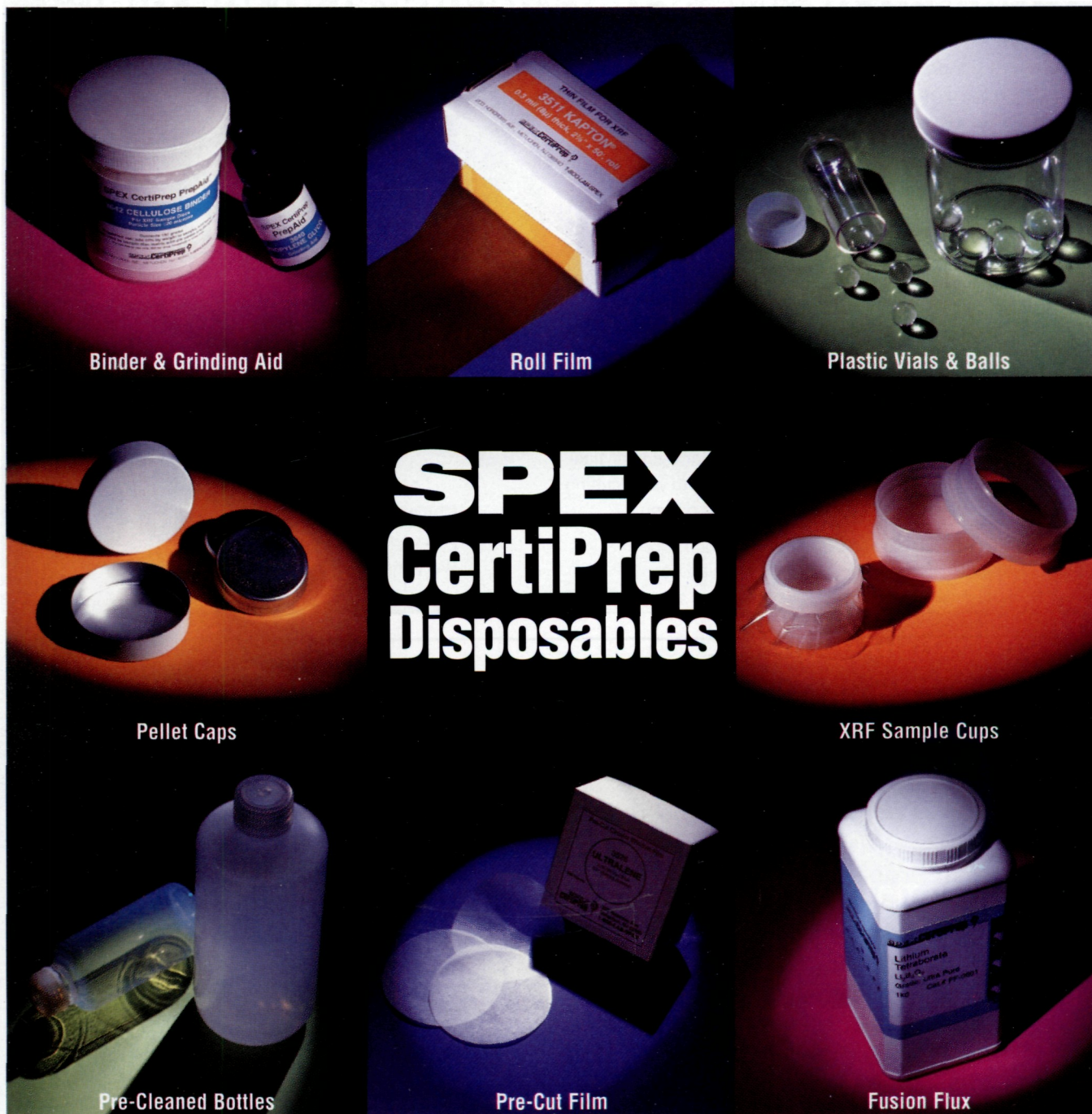
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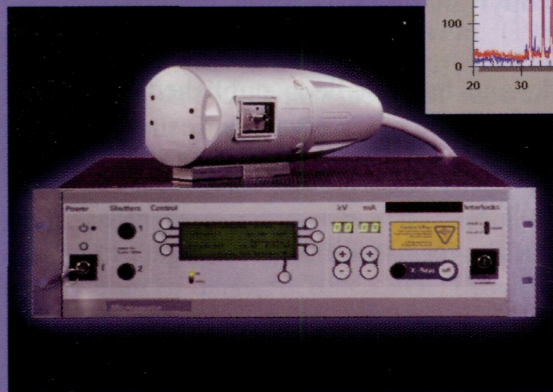
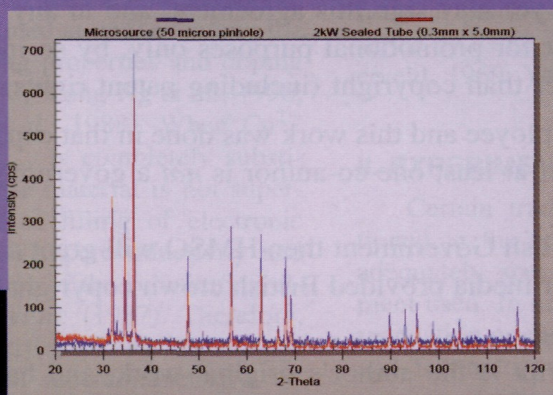
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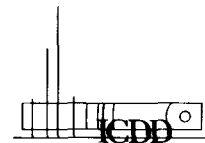
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